

“Three Approaches for Representing the Statistical Uncertainty on Atom-Counting Results in Quantitative ADF STEM”. De wael A, De Backer A, Yu C-P, Sentürk DG, Lobato I, Faes C, Van Aert S, *Microscopy and microanalysis* , 1 (2022).
<http://doi.org/10.1017/S1431927622012284>